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PATENT APPLICATION
PO-8734
BTS054034

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICATION OF)
MARKUS HAIML ET AL)
SERIAL NUMBER: 10/565,909)
DATE SUBMITTED: JANUARY 25, 2006)
TITLE: ANALYTICAL SYSTEM, AND)
METHOD FOR ANALYZING)
NONLINEAR OPTICAL SIGNALS)

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This disclosure statement under 37 CFR 1.97 & 1.98 is submitted before the first Office Action in order that the Patent and Trademark Office may consider the relevancy of certain information to the invention described and claimed in the subject application, and in compliance with the regulations concerning information disclosure statements. Copies of the foreign documents and articles listed on the attached Form PTO-1449 are enclosed.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an enveloped addressed to: Commissioner for Patents, Alexandria, VA 22313-1450 on 9/20/06

Date

Aron Preis, Reg. No. 29,426

Name of applicant, assignee or Registered Representative

Signature

September 20, 2006

Date

Concise statements of the presently understood relevance of each of the documents are found in the specification filed.

This Information Disclosure Statement should not be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, that any document mentioned herein constitutes prior art, or that the documents listed severally or in any combination with one another or with any other information, are believed to render any claim in the subject application prima facie unpatentable.

Respectfully submitted,

By



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Form PTO 1449 Rev. 7-80	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No. PO8734/BTS054034	Serial No. 10/565,909
LIST OF PRIOR ART CITED BY APPLICANT (Use Several Sheets If Necessary)		Applicant Markus Haiml et al	
		Filing Date January 25, 2006	Group No.

SEP 22 2006

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		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	AB	**5,034,613	07/23/91	Denk et al	250	458.1	
	AC	5,445,934	08/29/95	Fodor et al	435	6	
	AD	**5,459,574	10/17/95	Lee et al	356	437	
	AE	5,742,355	04/21/98	(Bel. to corresp. to WO De Haan et al	96/15625) 348	607	
	AF	5,822,472	10/13/98	(Bel. to corresp. to WO Danielzik et al	95/33198) 385	12	
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	AM	01/13096 A1	02/22/01	World				X
	AN	02/46756 A1	06/13/02	World				X
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	AR	Science, 248, April 6, 1990, pages 73-76, Winfried Denk et al, "Two-Photon Laser Scanning Fluorescence Microscopy"
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	AT	Analytica Chimica Acta, 469, (month unavailable) 2002, pages 49-61, Gert L. Duveneck et al, "Planar waveguides for ultra-high sensitivity of the analysis of nucleic acids"

EXAMINER

DATE CONSIDERED

EXAMINER Initial if references considered, whether or not citation is in conformance with MPEP 609: Draw line through if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	Markus Haiml et al	
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	AA	6,384,912 B2	05/07/02	(Bel. to corresp. to WO Kraus et al	98/22799) 356	246	
	AB	6,437,345 B1	08/20/02	(Bel. to corresp. to WO Bruno-Raimondi et al	99/58963) 250	458.1	
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	AF	7,060,957 B2	06/13/06	(Bel. to corresp. to WO Lange et al	01/84182) 250	208.1	
	AG	2001/0001021 A1	05/10/01	(Bel. to corresp. to WO Kraus et al	98/22799) 385	12	
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	AH						
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